INTEGRATED CIRCUITS

DATA SHEET

74ALVT16899

2.5V/3.3V 18-bit latched transceiver with 16-bit parity generator/checker (3-State)

Product specification IC23 Data Handbook





2.5V/3.3V 18-bit latched transceiver with 16-bit parity generator/checker (3-State)

74ALVT16899

FEATURES

- Symmetrical (A and B bus functions are identical)
- Selectable generate parity or "feed-through" parity for A-to-B and B-to-A directions
- Independent transparent latches for A-to-B and B-to-A directions
- Selectable ODD/EVEN parity
- Continuously checks parity of both A bus and B bus latches as ERRA and ERRB
- Open-collector ERR output
- Ability to simultaneously generate and check parity
- Can simultaneously read/latch A and B bus data
- Output capability: +64 mA/-32mA
- Latch-up protection exceeds 500mA per Jedec Std 17
- ESD protection exceeds 2000 V per MIL STD 883 Method 3015 and 200 V per Machine Model
- Power up 3-State
- Power-up reset
- No bus current loading when output is tied to 5 V bus
- Live insertion/extraction permitted
- Bus-hold data inputs eliminate the need for external pull-up resistors to hold unused inputs

DESCRIPTION

The 74ALVT16899 is a high-performance BiCMOS product designed for V_{CC} operation at 2.5V or 3.3V with I/O compatibility up to 5V.

The 74ALVT16899 is a 16-bit to 16-bit parity transceiver with separate transparent latches for the A bus and B bus. Either bus

can generate or check parity. The parity bit can be fed-through with no change or the generated parity can be substituted with the $\overline{\text{SEL}}$ input.

The 74ALVT16899 features independent latch enables for the A and B bus latches, a select pin for ODD/EVEN parity, and separate error signal output pins for checking parity.

FUNCTIONAL DESCRIPTION:

The 74ALVT16899 has three principal modes of operation which are outlined below. All modes apply to both the A-to-B and B-to-A directions.

Transparent latch, Generate parity, Check A and B bus parity: Bus A (B) communicates to Bus B (A), parity is generated and passed on to the B (A) Bus as BPAR (APAR). If LEA and LEB are High and the Mode Select (SEL) is Low, the parity generated from A0-A7 and B0-B7 can be checked and monitored by ERRA and ERRB. (Fault detection on both input and output buses.)

Transparent latch, Feed-through parity, Check A and B bus parity:

Bus A (B) communicates to Bus B (A) in a feed-through mode if SEL is High. Parity is still generated and checked as ERRA and ERRB and can be used as an interrupt to signal a data/parity bit error to the CPU.

Latched input, Generate/Feed-through parity, Check A (and B) bus parity:

Independent latch enables (LEA and LEB) allow other permutations of:

- Transparent latch / 1 bus latched / both buses latched
- Feed-through parity / generate parity
- Check in bus parity / check out bus parity / check in and out bus parity

QUICK REFERENCE DATA

0)/440.01		CONDITIONS	TYPI		
SYMBOL	PARAMETER	T _{amb} = 25°C; GND = 0V	2.5 V	3.3 V	UNIT
t _{PLH} t _{PHL}	Propagation delay An to Bn or Bn to An	C _L = 50pF	2.0 2.2	1.5 1.7	ns
t _{PLH} t _{PHL}	Propagation delay An to ERRA	C _L = 50pF	9.8 7.0	7.8 5.1	ns
C _{IN}	Input capacitance	$V_I = 0V \text{ or } V_{CC}$	3	3	pF
C _{I/O}	Output capacitance	Outputs disabled; $V_O = 0V$ or V_{CC}	9	9	pF
I _{CCZ}	Quiescent supply current	Outputs disabled	40	70	μА

ORDERING INFORMATION

PACKAGES	TEMPERATURE RANGE	OUTSIDE NORTH AMERICA	NORTH AMERICA	DWG NUMBER
56-Pin Plastic SSOP Type III	-40°C to +85°C	74ALVT16899	AV16899 DL	SOT371-1
56-Pin Plastic TSSOP Type II	-40°C to +85°C	74ALVT16899 DGG	AV16899 DGG	SOT364-1

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PIN CONFIGURATION

		7	1	
ODD/EVEN	1		56	SEL
ŌĒĀ	2		55	LEA
1A0	3		54	1B0
GND	4		53	GND
1A1	5		52	1B1
1A2	6		51	1B2
1A3	7		50	1B3
1A4	8		49	1B4
Vcc	9		48	V _{CC}
1A5	10		47	1B5
1A6	11		46	1B6
1A7	12		45	1B7
1APAR	13		44	1BPAR
1ERRA	14		43	1ERRB
GND	15		42	GND
2ERRA	16		41	2ERRB
2APAR	17		40	2BPAR
2A7	18		39	2B7
2A6	19		38	2B6
2A5	20		37	2B5
V _{CC}	21		36	V _{CC}
2A4	22		35	2B4
2A3	23		34	2B3
2A2	24		33	2B2
2A1	25		32	2B1
GND	26		31	GND
2A0	27		30	2B0
LEB	28		29	OEB
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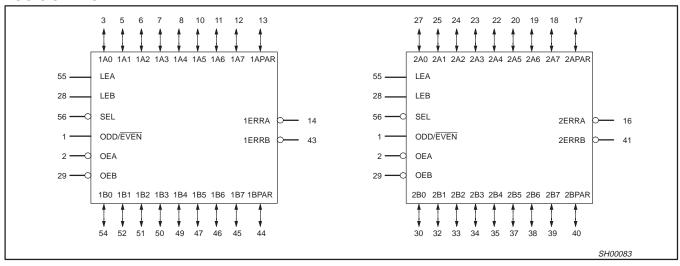
PIN DESCRIPTION

SYMBOL	PIN NUMBER	NAME AND FUNCTION
1A0 - 1A7 2A0 - 2A7	3, 5, 6, 7, 8, 10, 11, 12 27, 25, 24, 23, 22, 20, 19, 18	Latched A bus 3-State inputs/outputs
1B0 - 1B7 2B0 - 2B7	54, 52, 51, 50, 49, 47, 46, 45 30, 32, 33, 34, 35, 37, 38, 39	Latched B bus 3-State inputs/outputs
1APAR 2APAR	13, 17	A bus parity 3-State input/output
1BPAR 2BPAR	44, 40	B bus parity 3-State input/output
ODD/EVEN	1	Parity select input (Low for EVEN parity)
OEA, OEB	2, 29	Output enable inputs (gate A to B, B to A)
SEL	56	Mode select input (Low for generate)
LEA, LEB	55, 28	Latch enable inputs (transparent High)
1ERRA, 1ERRB 2ERRA, 2ERRB	14, 43, 16, 41	Error signal outputs (active-Low)
GND	4, 15, 26, 31, 42, 53	Ground (0V)
V _{CC}	9, 21, 36, 48	Positive supply voltage

2.5V/3.3V 18-bit latched transceiver with 16-bit parity generator/checker (3-State)

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LOGIC SYMBOL



PARITY AND ERROR FUNCTION TABLE

	INPU	гѕ			OUTPUTS			
SEL	ODD/EVEN	xPAR (A or B)	Σ of High Inputs	xPAR (B or A)	ERRt	ERRr*		PARITY MODES
Н	Н	Н	Even Odd	H H	H L	H L	Odd	
Н	Н	L	Even Odd	L L	L H	L H	Mode	Feed-through/check parity
Н	L	Н	Even Odd	H H	L H	L H	Even	
Н	L	L	Even Odd	L	H	H L	Mode	
L	Н	Н	Even Odd	ΗL	ΗL	H H	Odd	
L	Н	L	Even Odd	ΗL	L H	H H	Mode	Generate parity
L	L	Н	Even Odd	LH	L	H H	Even	
L	L	L	Even Odd	L H	H	H H	Mode	

High voltage level

Low voltage level

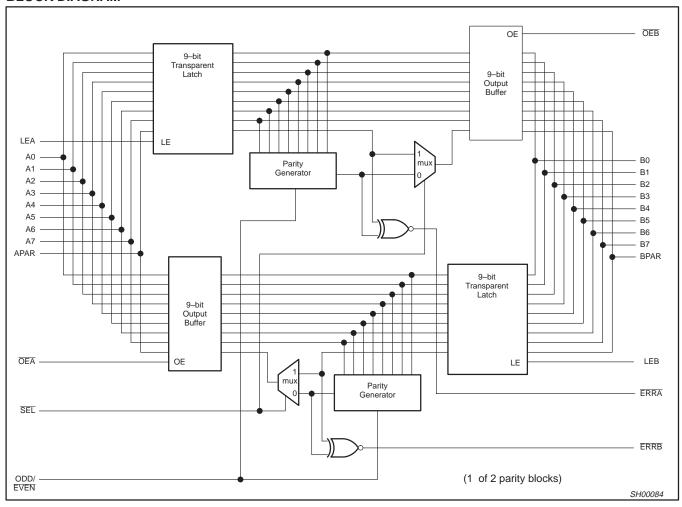
Transmit–if the data path is from A→B then <u>ERRt</u> is <u>ERRA</u> Receive–if the data path is from A→B then <u>ERRr</u> is <u>ERRB</u>

Blocked if latch is not transparent

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BLOCK DIAGRAM



FUNCTION TABLE

	ı	NPUTS	3		OPERATING MODE
OEB	OEA	SEL	LEA	LEB	
Н	Н	Х	Х	Х	3-State A bus and B bus (input A & B simultaneously)
Н	L	L	L	Н	${\sf B} ightarrow {\sf A}$, transparent B latch, generate parity from B0 - B7, check B bus parity
Н	L	L	Н	Н	B o A, transparent A & B latch, generate parity from B0 - B7, check A & B bus parity
Н	L	L	Х	L	B ightarrow A, B bus latched, generate parity from latched B0 - B7 data, check B bus parity
Н	L	Н	Х	Н	B o A, transparent B latch, parity feed-through, check B bus parity
Н	L	Н	Н	Н	B o A, transparent A & B latch, parity feed-through, check A & B bus parity
L	Н	L	Н	Х	A o B, transparent A latch, generate parity from A0 - A7, check A bus parity
L	Н	L	Н	Н	A o B, transparent A & B latch, generate parity from A0 - A7, check A & B bus parity
L	Н	L	L	Х	A ightarrow B, A bus latched, generate parity from latched A0 - A7 data, check A bus parity
L	Н	Н	Н	L	$A \to B$, transparent A latch, parity feed-through, check A bus parity
L	Н	Н	Н	Н	A o B, transparent A & B latch, parity feed-through, check A & B bus parity
L	L	Х	Х	Х	Output to A bus and B bus (NOT ALLOWED)

H = High voltage level

L = Low voltage level

X = Don't care

2.5V/3.3V 18-bit latched transceiver with 16-bit parity generator/checker (3-State)

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ABSOLUTE MAXIMUM RATINGS1, 2

SYMBOL	PARAMETER	CONDITIONS	RATING	UNIT
V _{CC}	DC supply voltage		-0.5 to +4.6	V
I _{IK}	DC input diode current	V _I < 0	-50	mA
VI	DC input voltage ³		-0.5 to +7.0	V
I _{OK}	DC output diode current	V _O < 0	-50	mA
V _{OUT}	DC output voltage ³	Output in Off or High state	-0.5 to +7.0	V
lau-	DC output current	Output in Low state	128	mA
IOUT	De output current	Output in High state	-64	IIIA
T _{stg}	Storage temperature range		-65 to +150	°C

NOTES:

Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the
device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to
absolute-maximum-rated conditions for extended periods may affect device reliability.

The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150°C.

3. The input and output negative voltage ratings may be exceeded if the input and output clamp current ratings are observed.

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	2.5V RANG	GE LIMITS	3.3V RANG	UNIT	
STWIBOL	TANAMETER	MIN	MAX	MIN	MAX	ONIT
V _{CC}	DC supply voltage	2.3	2.7	3.0	3.6	V
VI	Input voltage	0	5.5	0	5.5	V
V _{IH}	High-level input voltage	1.7		2.0		V
V _{IL}	Input voltage		0.7		0.8	V
I _{OH}	High-level output current		-8		-32	mA
lou	Low-level output current		8		32	mA
l _{OL}	Low-level output current; current duty cycle ≤ 50%; f ≥ 1kHz		24		64	ША
Δt/Δν	Input transition rise or fall rate; Outputs enabled		10		10	ns/V
T _{amb}	Operating free-air temperature range	-40	+85	-40	+85	°C

2.5V/3.3V 18-bit latched transceiver with 16-bit parity generator/checker (3-State)

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DC ELECTRICAL CHARACTERISTICS (3.3V \pm 0.3V RANGE)

					LIMITS		
SYMBOL	PARAMETER	TEST CONDITIONS		Temp =	-40°C to	+85°C	UNIT
				MIN	TYP ¹	MAX	
V _{IK}	Input clamp voltage	$V_{CC} = 3.0V; I_{IK} = -18mA$			-0.85	-1.2	V
W	High-level output voltage	$V_{CC} = 3.0 \text{ to } 3.6\text{V}; I_{OH} = -100\mu\text{A}$		V _{CC} -0.2	V _{CC}		V
V _{OH}	High-level output voltage	$V_{CC} = 3.0V; I_{OH} = -32mA$		2.0	2.3		V
		$V_{CC} = 3.0V; I_{OL} = 100\mu A$			0.07	0.2	
V _{OL}	Low-level output voltage	$V_{CC} = 3.0V; I_{OL} = 16mA$			0.25	0.4	V
VOL	Low level output voltage	$V_{CC} = 3.0V; I_{OL} = 32mA$			0.3	0.5	·
		$V_{CC} = 3.0V; I_{OL} = 64mA$			0.4	0.55	
V_{RST}	Power-up output low voltage ⁶	$V_{CC} = 3.6V$; $I_O = 1mA$; $V_I = V_{CC}$ or GND				0.55	V
		$V_{CC} = 3.6V$; $V_I = V_{CC}$ or GND	Control pins		0.1	±1	
		V _{CC} = 0 or 3.6V; V _I = 5.5V	Control pins		0.1	10	
II	$V_{CC} = 3.6V; V_I = V_{CC}$ Data pins ⁴		0.1	20	μΑ		
		$V_{CC} = 3.6V; V_{I} = V_{CC}$	Data pins ⁴		0.5	1	
		V _{CC} = 3.6V; V _I = 0V			0.1	-5	
I _{OFF}	Off current	$V_{CC} = 0V$; V_I or $V_O = 0$ to 4.5V			0.1	±100	μΑ
	Bus Hold current	$V_{CC} = 3V; V_I = 0.8V$		75	130		
I _{HOLD}	Data inputs	V _{CC} = 3V; V _I = 2.0V		-75	-140		μΑ
	Data iriputs	$V_1 = 0V \text{ to } 3.6V; V_{CC} = 3.6V^7$		±500			
I _{EX}	Current into an output in the High state when V _O > V _{CC}	V _O = 5.5V; V _{CC} = 3.0V			10	125	μА
I _{PU/PD}	Power up/down 3-State output current ³	$V_{CC} \le 1.2V$; $V_O = 0.5V$ to V_{CC} ; $V_I = GNDOE/OE = Don't$ care	or V _{CC}		33	±100	μА
I _{OZH}	3-State output High current	$V_{CC} = 3.6V; V_{O} = 3.0V; V_{I} = V_{IL} \text{ or } V_{IH}$			0.5	5	μΑ
l _{OZL}	3-State output Low current	$V_{CC} = 3.6V; V_{O} = 0.5V; V_{I} = V_{IL} \text{ or } V_{IH}$			0.5	- 5	μΑ
I _{CCH}		$V_{CC} = 3.6V$; Outputs High, $V_I = GND$ or V_{CC} , $I_O = 0$			0.05	0.1	
I _{CCL}	Quiescent supply current	$V_{CC} = 3.6V$; Outputs Low, $V_I = GND$ or $V_I = GND$	$I_{CC, I_O} = 0$		4.6	7.0	mA
I _{CCZ}	1	V _{CC} = 3.6V; Outputs Disabled; V _I = GND	or V_{CC} , $I_{O} = 0^{5}$		0.06	0.1	
Δl _{CC}	Additional supply current per input pin ²	V_{CC} = 3V to 3.6V; One input at V_{CC} -0.6V Other inputs at V_{CC} or GND	V,		0.04	0.4	mA

NOTES:

- All typical values are at V_{CC} = 3.3V and T_{amb} = 25°C.
 This is the increase in supply current for each input at the specified voltage level other than V_{CC} or GND
- This is the increase in supply calculated the specified voltage level office than V_{CC} of SND
 This parameter is valid for any V_{CC} between 0V and 1.2V with a transition time of up to 10msec. From V_{CC} = 1.2V to V_{CC} = 3.3V ± 0.3V a transition time of 100µsec is permitted. This parameter is valid for T_{amb} = 25°C only.
 Unused pins at V_{CC} or GND.
 I_{CCZ} is measured with outputs pulled up to V_{CC} or pulled down to ground.

- 6. For valid test results, data must not be loaded into the flip-flops (or latches) after applying power.
- 7. This is the bus hold overdrive current required to force the input to the opposite logic state.

2.5V/3.3V 18-bit latched transceiver with 16-bit parity generator/checker (3-State)

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AC CHARACTERISTICS (3.3V \pm 0.3V RANGE)

GND = 0V; $t_R = t_F = 2.5 \text{ns}$; $C_L = \dot{50} \text{pF}$; $R_L = 500 \Omega$; $T_{amb} = -\dot{40} ^{\circ} \text{C}$ to +85°C.

				LIMITS $V_{CC} = 3.3V \pm 0.3V$				
SYMBOL	PARAMETER	WAVEFORM	V					
			MIN	TYP ¹	MAX	1		
t _{PLH} t _{PHL}	Propagation delay An to Bn or Bn to An	1	0.5 0.5	1.5 1.7	2.7 2.8	ns		
t _{PLH} t _{PHL}	Propagation delay An to BPAR or Bn to APAR	4	2.5 2.0	5.0 4.6	8.0 7.3	ns		
t _{PLH} t _{PHL}	Propagation delay An to ERRA or Bn to ERRB	5	2.5 2.5	7.8 5.1	11.5 8.5	ns		
t _{PLH} t _{PHL}	Propagation delay APAR to BPAR or BPAR to APAR	3	1.0 1.0	2.9 3.0	6.9 6.4	ns		
t _{PLH} t _{PHL}	Propagation delay APAR to ERRA or BPAR to ERRB	8	2.5 1.0	5.1 2.5	8.0 3.6	ns		
t _{PLH} t _{PHL}	Propagation delay ODD/EVEN to APAR or BPAR	7	1.5 1.5	3.8 3.4	6.5 5.4	ns		
t _{PLH} t _{PHL}	Propagation delay ODD/EVEN to ERRA or ERRB	6	2.5 1.5	6.6 4.0	10.0 6.6	ns		
t _{PLH} t _{PHL}	Propagation delay SEL to APAR or BPAR	10	1.0 1.0	2.6 2.4	4.0 3.4	ns		
t _{PLH} t _{PHL}	Propagation delay SEL to ERRA or ERRB	5	2.5 1.5	7.8 4.8	10.8 7.1	ns		
t _{PLH} t _{PHL}	Propagation delay LEA to Bn or LEB to An	11	1.0 1.0	2.2 2.2	3.8 3.8	ns		
t _{PLH} t _{PHL}	Propagation delay LEA to BPAR or LEB to APAR	11	2.5 2.0	5.3 4.9	8.5 7.6	ns		
t _{PLH} t _{PHL}	Propagation delay LEA to ERRA or LEB to ERRB	9	2.5 2.5	7.4 5.6	11.0 9.2	ns		
t _{PZH} t _{PZL}	Output enable time OEA to An, APAR or OEB to Bn, BPAR	13, 14	1.0 0.5	2.4 1.8	5.8 3.3	ns		
t _{PHZ}	Output disable time OEA to An, APAR or OEB to Bn, BPAR	13, 14	2.5 1.0	5.2 2.4	8.0 3.5	ns		

NOTE:

AC SETUP REQUIREMENTS (3.3V \pm 0.3V RANGE)

GND = 0V; $t_R = t_F = 2.5$ ns; $C_L = 50$ pF, $R_L = 500\Omega$

			LIN		
SYMBOL	PARAMETER	WAVEFORM	V _{CC} = 3.	UNIT	
			MIN	TYP	
t _S (H) t _S (L)	Setup time, High or Low An, APAR to LEA or Bn, BPAR to LEB	12	1.0 1.0	0.1 0.1	ns
t _h (H) t _h (L)	Hold time, High or Low An, APAR to LEA or Bn, BPAR to LEB	12	1.0 1.0	-0.1 0.1	ns
t _w (H)	Pulse width, High LEA or LEB	12	1.0	-	ns

^{1.} All typical values are at V_{CC} = 3.3V and T_{amb} = 25°C.

2.5V/3.3V 18-bit latched transceiver with 16-bit parity generator/checker (3-State)

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DC ELECTRICAL CHARACTERISTICS (2.5V \pm 0.2V RANGE)

					LIMITS		
SYMBOL	PARAMETER	TEST CONDITIONS		Temp =	-40°C to	+85°C	UNIT
			MIN	TYP ¹	MAX		
V _{IK}	Input clamp voltage	$V_{CC} = 2.3V; I_{IK} = -18mA$			-0.85	-1.2	V
V _{OH}	High-level output voltage	$V_{CC} = 2.3 \text{ to } 3.6 \text{V}; I_{OH} = -100 \mu\text{A}$		V _{CC} -0.2	V _{CC}		V
VOH	I light-level output voltage	$V_{CC} = 2.3V; I_{OH} = -8mA$		1.8	2.5		ľ
		$V_{CC} = 2.3V; I_{OL} = 100\mu A$			0.07	0.2	
V_{OL}	Low-level output voltage	$V_{CC} = 2.3V; I_{OL} = 24mA$			0.3	0.5	V
		$V_{CC} = 2.3V; I_{OL} = 8mA$				0.4	
V_{RST}	Power-up output low voltage ⁷	$V_{CC} = 2.7V; I_{O} = 1mA; V_{I} = V_{CC} \text{ or GND}$				0.55	V
		$V_{CC} = 2.7V$; $V_I = V_{CC}$ or GND	Control pins		0.1	±1	
		$V_{CC} = 0 \text{ or } 2.7V; V_{I} = 5.5V$	Control pins		0.1	10	1
II	Input leakage current	$V_{CC} = 2.7V; V_I = 5.5V$			0.1	20	μΑ
		$V_{CC} = 2.7V; V_{I} = V_{CC}$	Data pins ⁴		0.1	10	
		$V_{CC} = 2.7V; V_I = 0$			0.1	-5	
I _{OFF}	Off current	$V_{CC} = 0V; V_{I} \text{ or } V_{O} = 0 \text{ to } 4.5V$			0.1	±100	μΑ
l 6	Bus Hold current	$V_{CC} = 2.3V; V_I = 0.7V$			115		μΑ
HOLD ⁶	Data inputs	$V_{CC} = 2.3V; V_I = 1.7V$			10		μΑ
I _{EX}	Current into an output in the High state when V _O > V _{CC}	V _O = 5.5V; V _{CC} = 2.3V			10	125	μА
I _{PU/PD}	Power up/down 3-State output current ³	$V_{CC} \le 1.2V$; $V_O = 0.5V$ to V_{CC} ; $V_I = GNDOE/OE/OE$ = Don't care	or V _{CC} ;		33	±100	μА
I _{OZH}	3-State output High current	$V_{CC} = 2.7V$; $V_{O} = 2.3V$; $V_{I} = V_{IL}$ or V_{IH}			0.5	5	μΑ
I _{OZL}	3-State output Low current	$V_{CC} = 2.7V; V_{O} = 0.5V; V_{I} = V_{IL} \text{ or } V_{IH}$			0.5	-5	μΑ
I _{CCH}		$V_{CC} = 2.7V$; Outputs High, $V_I = GND$ or $V_{CC} = 0.00$	V_{CC} , $I_O = 0$		0.04	0.1	
I _{CCL}	Quiescent supply current	$V_{CC} = 2.7V$; Outputs Low, $V_I = GND$ or V_{CC} , $I_O = 0$			3.5	4.5	mΑ
I _{CCZ}	1	V _{CC} = 2.7V; Outputs Disabled; V _I = GND	or V_{CC} , $I_{O} = 0^{5}$		0.04	0.1	
ΔI_{CC}	Additional supply current per input pin ²	V_{CC} = 2.3V to 2.7V; One input at V_{CC} -0. Other inputs at V_{CC} or GND	6V,		0.04	0.4	mA

NOTES:

- All typical values are at V_{CC} = 2.5V and T_{amb} = 25°C.
 This is the increase in supply current for each input at the specified voltage level other than V_{CC} or GND
 This parameter is valid for any V_{CC} between 0V and 1.2V with a transition time of up to 10msec. From V_{CC} = 1.2V to V_{CC} = 2.5V ± 0.2V a transition time of 100µsec is permitted. This parameter is valid for T_{amb} = 25°C only.
 Unused pins at V_{CC} or GND.
- 5. I_{CCZ} is measured with outputs pulled up to V_{CC} or pulled down to ground.
 6. Not guaranteed.
- 7. For valid test results, data must not be loaded into the flip-flops (or latches) after applying power.

2.5V/3.3V 18-bit latched transceiver with 16-bit parity generator/checker (3-State)

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AC CHARACTERISTICS (2.5V \pm 0.2V RANGE)

GND = 0V; $t_R = t_F = 2.5 ns$; $C_L = 50 pF$; $R_L = 500 \Omega$; $T_{amb} = -40 ^{\circ} C$ to $+85 ^{\circ} C$.

SYMBOL	PARAMETER	WAVEFORM	V	UNIT		
			MIN	MIN TYP ¹ MAX		
t _{PLH} t _{PHL}	Propagation delay An to Bn or Bn to An	1	1.0 1.0	2.0 2.2	3.5 3.9	ns
t _{PLH} t _{PHL}	Propagation delay An to BPAR or Bn to APAR	4	3.0 3.0	7.0 6.5	10.5 10.2	ns
t _{PLH} t _{PHL}	Propagation delay An to ERRA or Bn to ERRB	5	4.5 3.5	9.8 7.0	14.5 11.5	ns
t _{PLH} t _{PHL}	Propagation delay APAR to BPAR or BPAR to APAR	3	1.0 1.0	3.0 3.5	4.3 5.5	ns
t _{PLH} t _{PHL}	Propagation delay APAR to ERRA or BPAR to ERRB	8	3.0 1.5	6.7 3.6	10.0 5.4	ns
t _{PLH} t _{PHL}	Propagation delay ODD/EVEN to APAR or BPAR	7	2.5 2.5	5.2 5.0	7.8 7.8	ns
t _{PLH} t _{PHL}	Propagation delay ODD/EVEN to ERRA or ERRB	6	4.0 4.0	8.6 8.1	12.0 10.6	ns
t _{PLH} t _{PHL}	Propagation delay SEL to APAR or BPAR	10	1.5 1.5	3.7 3.2	5.5 5.3	ns
t _{PLH} t _{PHL}	Propagation delay SEL to ERRA or ERRB	5	4.5 3.0	9.4 7.6	14.0 11.5	ns
t _{PLH} t _{PHL}	Propagation delay LEA to Bn or LEB to An	11	1.0 1.0	3.0 3.0	4.8 4.6	ns
t _{PLH} t _{PHL}	Propagation delay LEA to BPAR or LEB to APAR	11	2.5 2.5	7.5 7.4	12.2 11.2	ns
t _{PLH} t _{PHL}	Propagation delay LEA to ERRA or LEB to ERRB	9	4.5 3.5	9.7 8.5	15.0 13.4	ns
t _{PZH} t _{PZL}	Output enable time OEA to An, APAR or OEB to Bn, BPAR	13, 14	1.5 1.0	4.0 2.6	6.0 4.6	ns
t _{PHZ}	Output disable time OEA to An, APAR or OEB to Bn, BPAR	13, 14	1.5 1.0	4.5 3.7	6.5 5.0	ns

NOTE:

AC SETUP REQUIREMENTS (2.5V \pm 0.2V RANGE)

GND = 0V; $t_R = t_F = 2.5 \text{ns}$; $C_L = 50 \text{pF}$, $R_L = 500 \Omega$; $T_{amb} = -40 ^{\circ} \text{C}$ to $+85 ^{\circ} \text{C}$.

			LIN	IITS	
SYMBOL	PARAMETER	WAVEFORM	V _{CC} = 2.	UNIT	
			MIN	TYP	
$t_{s}(H)$ $t_{s}(L)$	Setup time, High or Low An, APAR to LEA or Bn, BPAR to LEB	12	-1.0 1.2	-0.4 0.4	ns
$t_h(H)$ $t_h(L)$	Hold time, High or Low An, APAR to LEA or Bn, BPAR to LEB	12	-1.0 1.2	-0.4 0.5	ns
t _w (H)	Pulse width, High LEA or LEB	12	1.0	_	ns

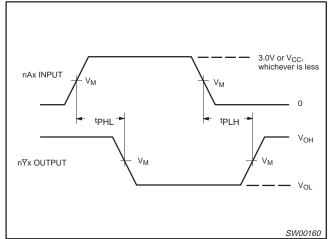
^{1.} All typical values are at V_{CC} = 2.5V and T_{amb} = 25°C.

2.5V/3.3V 18-bit latched transceiver with 16-bit parity generator/checker (3-State)

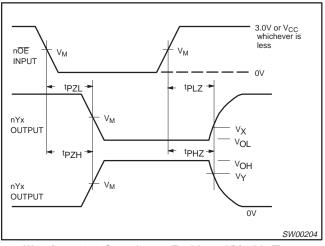
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AC WAVEFORMS

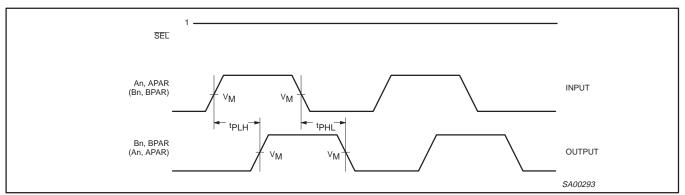
 $V_M = 1.5V$ or $V_{CC}/2$ whichever is less; $V_{IN} = GND$ to 3.0V



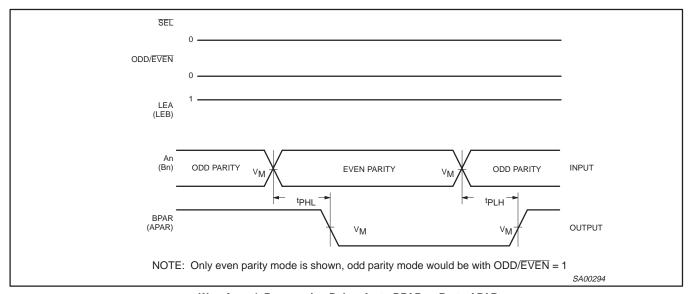
Waveform 1. Input (nAx) to Output (nYx) Propagation Delays



Waveform 2. 3-State Output Enable and Disable Times



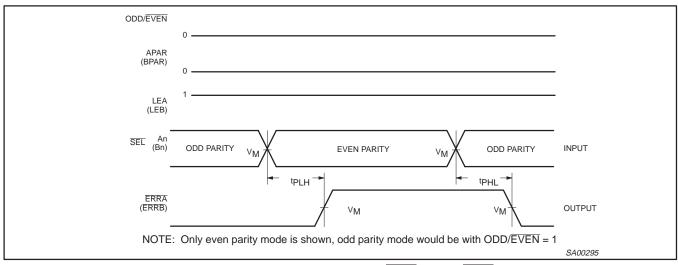
Waveform 3. Propagation Delay, An to Bn, Bn to An, APAR to BPAR, BPAR to APAR



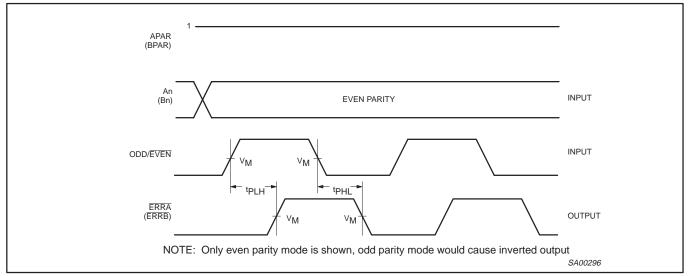
Waveform 4. Propagation Delay, An to BPAR or Bn to APAR

2.5V/3.3V 18-bit latched transceiver with 16-bit parity generator/checker (3-State)

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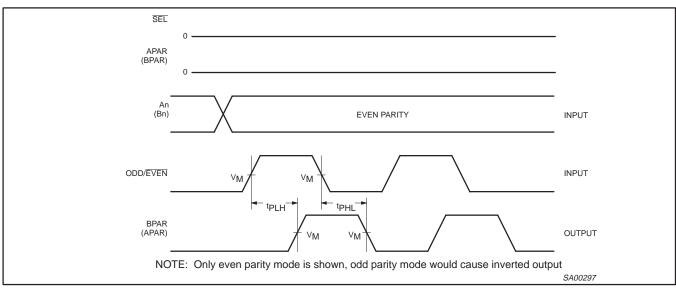
Waveform 5. Propagation Delay, An to ERRA or Bn to ERRB



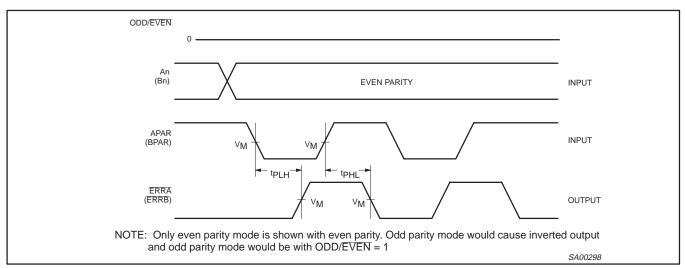
Waveform 6. Propagation Delay, ODD/EVEN to ERRA or ODD/EVEN to ERRB

2.5V/3.3V 18-bit latched transceiver with 16-bit parity generator/checker (3-State)

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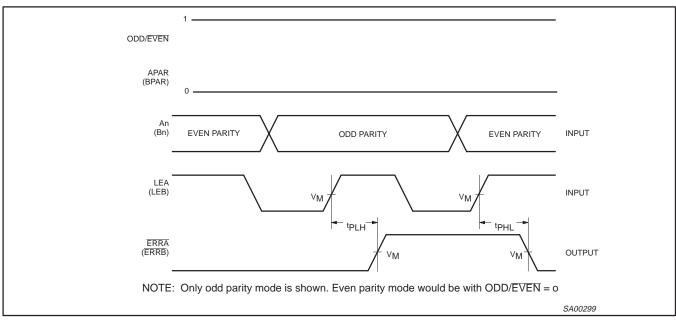
Waveform 7. Propagation Delay, ODD/EVEN to APAR or ODD/EVEN to BPAR



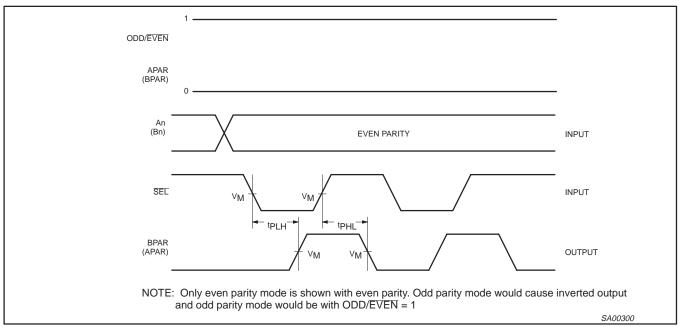
Waveform 8. Propagation Delay, APAR to ERRA or BPAR to ERRB

2.5V/3.3V 18-bit latched transceiver with 16-bit parity generator/checker (3-State)

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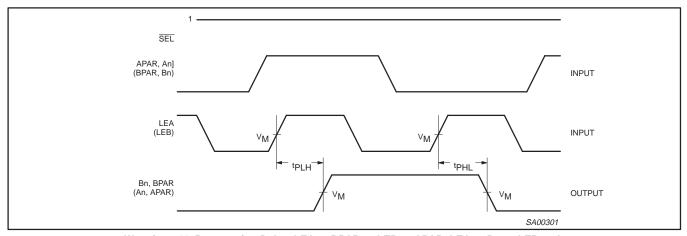
Waveform 9. Propagation Delay, LEA to ERRA or LEB to ERRB



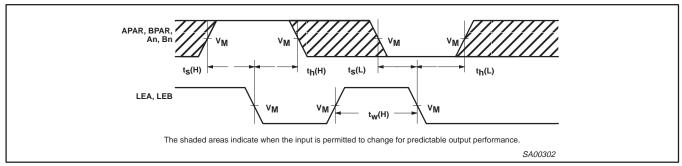
Waveform 10. Propagation Delay, SEL to BPAR or SEL to APAR

2.5V/3.3V 18-bit latched transceiver with 16-bit parity generator/checker (3-State)

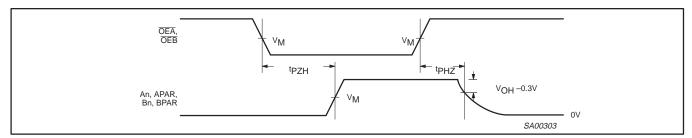
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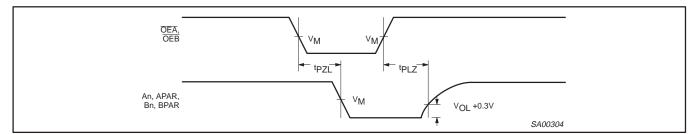
Waveform 11. Propagation Delay, LEA to BPAR or LEB to APAR, LEA to Bn or LEB to An



Waveform 12. Data Setup and Hold Times, Pulse Width High



Waveform 13. 3-State Output Enable Time to High Level and Output Disable Time from High Level

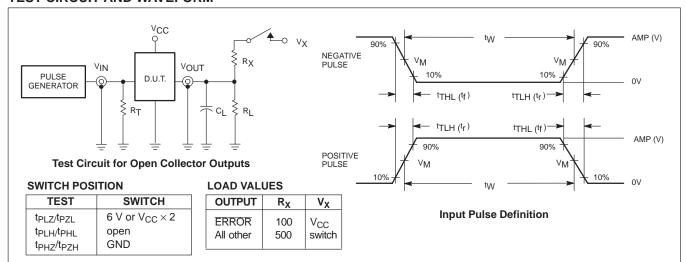


Waveform 14. 3-State Output Enable Time to Low Level and Output Disable Time from Low Level

2.5V/3.3V 18-bit latched transceiver with 16-bit parity generator/checker (3-State)

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TEST CIRCUIT AND WAVEFORM



DEFINITIONS:

R_L = Load resistor; see AC CHARACTERISTICS for value.

R_T = Termination resistance should be equal to Z_{OUT} of pulse generators.

FAMILY	INPUT PULSE REQUIREMENTS									
FAMILI	Amplitude	Rep. Rate	t _w	t _R	t _F					
74ALVT16	3.0V or V _{CC} , which ever is less	≤10MHz	500ns	≤ 2.5ns	≤ 2.5ns					

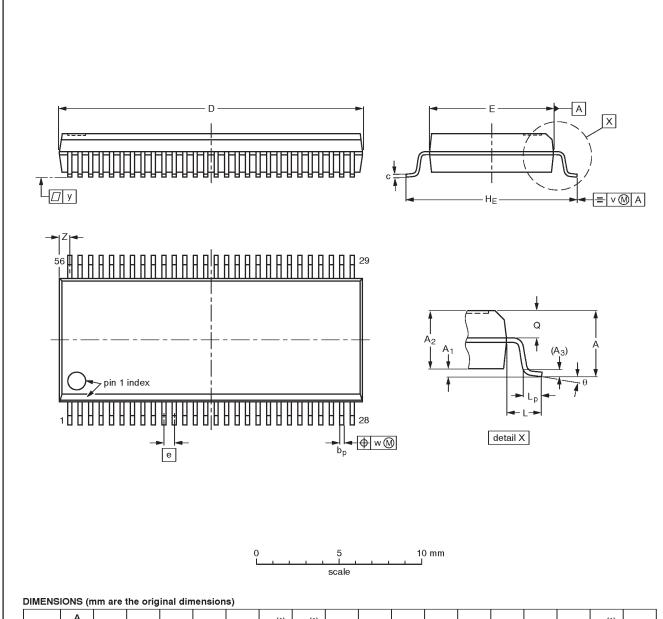
SV01732

2.5V/3.3V 18-bit latched transceiver with 16-bit parity generator/checker (3-State)

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SSOP56: plastic shrink small outline package; 56 leads; body width 7.5 mm

SOT371-1



UNIT	A max.	Α ₁	A ₂	A ₃	bp	С	D ⁽¹⁾	E ⁽¹⁾	е	HE	L	Lp	Q	v	w	у	Z ⁽¹⁾	θ
mm	2.8	0.4 0.2	2.35 2.20	0.25	0.3 0.2	0.22 0.13	18.55 18.30	7.6 7.4	0.635	10.4 10.1	1.4	1.0 0.6	1.2 1.0	0.25	0.18	0.1	0.85 0.40	8° 0°

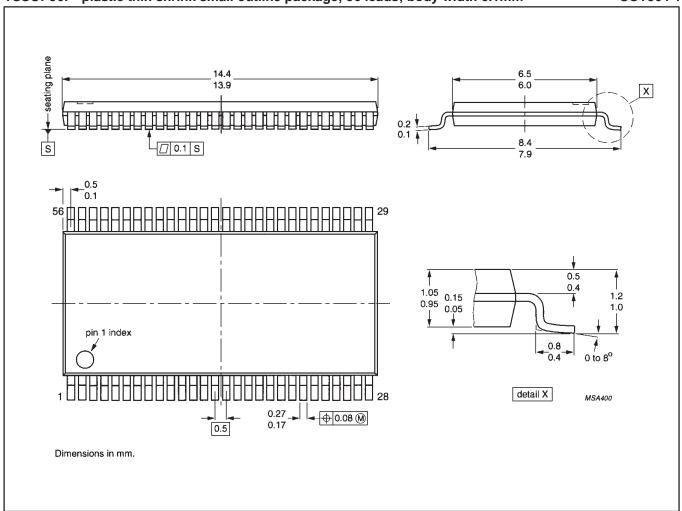
Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE		REFER	RENCES	EUROPEAN ISSUE DATE					
VERSION	IEC	JEDEC	EIAJ	PROJECTION	1330E DATE				
SOT371-1		MO-118AB			93-11-02 95-02-04				

TSSOP56: plastic thin shrink small outline package; 56 leads; body width 6.1mm

SOT364-1



2.5V/3.3V 18-bit latched transceiver with 16-bit parity generator/checker (3-State)

74ALVT16899

NOTES

2.5V/3.3V 18-bit latched transceiver with 16-bit parity generator/checker (3-State)

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Data sheet status

Data sheet status	Product status	Definition [1]
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
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^[1] Please consult the most recently issued datasheet before initiating or completing a design.

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Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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